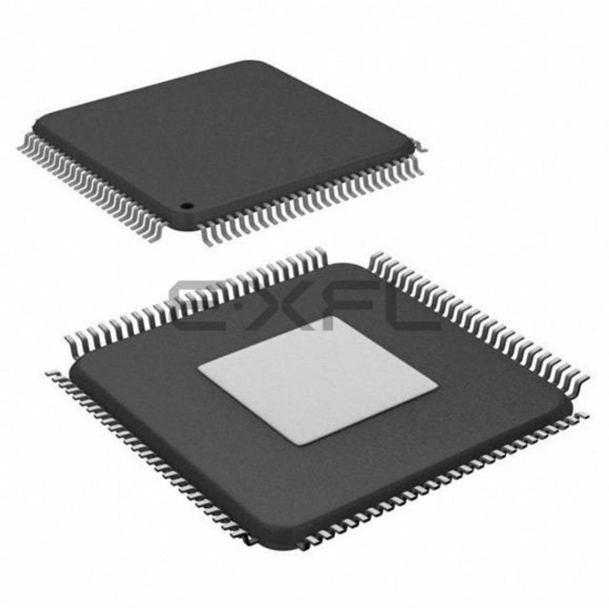

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	C166SV2
Core Size	16/32-Bit
Speed	66MHz
Connectivity	CANbus, EBI/EMI, I²C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I²S, POR, PWM, WDT
Number of I/O	76
Program Memory Size	320KB (320K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	42K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-100-8
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xc2263n40f66labfxuma1

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
45	P2.4	O0 / I	St/B	**Bit 4 of Port 2, General Purpose Input/Output**
	U0C1_DOUT	O1	St/B	**USIC0 Channel 1 Shift Data Output**
	TxDC0	O2	St/B	**CAN Node 0 Transmit Data Output**
	CC2_CC17	O3 / I	St/B	**CAPCOM2 CC17IO Capture Inp./ Compare Out.**
	A17	OH	St/B	**External Bus Interface Address Line 17**
	ESR1_0	I	St/B	**ESR1 Trigger Input 0**
	U0C0_DX0F	I	St/B	**USIC0 Channel 0 Shift Data Input**
	RxDC1A	I	St/B	**CAN Node 1 Receive Data Input**
46	P2.5	O0 / I	St/B	**Bit 5 of Port 2, General Purpose Input/Output**
	U0C0_SCLK OUT	O1	St/B	**USIC0 Channel 0 Shift Clock Output**
	TxDC0	O2	St/B	**CAN Node 0 Transmit Data Output**
	CC2_CC18	O3 / I	St/B	**CAPCOM2 CC18IO Capture Inp./ Compare Out.**
	A18	OH	St/B	**External Bus Interface Address Line 18**
	U0C0_DX1D	I	St/B	**USIC0 Channel 0 Shift Clock Input**
	ESR1_10	I	St/B	**ESR1 Trigger Input 10**
47	P4.2	O0 / I	St/B	**Bit 2 of Port 4, General Purpose Input/Output**
	TxDC2	O2	St/B	**CAN Node 2 Transmit Data Output**
	CC2_CC26	O3 / I	St/B	**CAPCOM2 CC26IO Capture Inp./ Compare Out.**
	$\overline{CS2}$	OH	St/B	**External Bus Interface Chip Select 2 Output**
	T2INA	I	St/B	**GPT12E Timer T2 Count/Gate Input**
48	P2.6	O0 / I	St/B	**Bit 6 of Port 2, General Purpose Input/Output**
	U0C0_SELO 0	O1	St/B	**USIC0 Channel 0 Select/Control 0 Output**
	U0C1_SELO 1	O2	St/B	**USIC0 Channel 1 Select/Control 1 Output**
	CC2_CC19	O3 / I	St/B	**CAPCOM2 CC19IO Capture Inp./ Compare Out.**
	A19	OH	St/B	**External Bus Interface Address Line 19**
	U0C0_DX2D	I	St/B	**USIC0 Channel 0 Shift Control Input**
	RxDC0D	I	St/B	**CAN Node 0 Receive Data Input**
	ESR2_6	I	St/B	**ESR2 Trigger Input 6**

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
58	P0.2	O0 / I	St/B	**Bit 2 of Port 0, General Purpose Input/Output**
	U1C0_SCLKOUT	O1	St/B	**USIC1 Channel 0 Shift Clock Output**
	TxDC0	O2	St/B	**CAN Node 0 Transmit Data Output**
	CCU61_CC62	O3	St/B	**CCU61 Channel 2 Output**
	A2	OH	St/B	**External Bus Interface Address Line 2**
	U1C0_DX1B	I	St/B	**USIC1 Channel 0 Shift Clock Input**
	CCU61_CC62INA	I	St/B	**CCU61 Channel 2 Input**
59	P10.0	O0 / I	St/B	**Bit 0 of Port 10, General Purpose Input/Output**
	U0C1_DOUT	O1	St/B	**USIC0 Channel 1 Shift Data Output**
	CCU60_CC60	O2	St/B	**CCU60 Channel 0 Output**
	AD0	OH / IH	St/B	**External Bus Interface Address/Data Line 0**
	CCU60_CC60INA	I	St/B	**CCU60 Channel 0 Input**
	ESR1_2	I	St/B	**ESR1 Trigger Input 2**
	U0C0_DX0A	I	St/B	**USIC0 Channel 0 Shift Data Input**
	U0C1_DX0A	I	St/B	**USIC0 Channel 1 Shift Data Input**
60	P10.1	O0 / I	St/B	**Bit 1 of Port 10, General Purpose Input/Output**
	U0C0_DOUT	O1	St/B	**USIC0 Channel 0 Shift Data Output**
	CCU60_CC61	O2	St/B	**CCU60 Channel 1 Output**
	AD1	OH / IH	St/B	**External Bus Interface Address/Data Line 1**
	CCU60_CC61INA	I	St/B	**CCU60 Channel 1 Input**
	U0C0_DX1A	I	St/B	**USIC0 Channel 0 Shift Clock Input**
	U0C0_DX0B	I	St/B	**USIC0 Channel 0 Shift Data Input**

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
69	P10.4	O0 / I	St/B	**Bit 4 of Port 10, General Purpose Input/Output**
	U0C0_SELO3	O1	St/B	**USIC0 Channel 0 Select/Control 3 Output**
	CCU60_COUT61	O2	St/B	**CCU60 Channel 1 Output**
	AD4	OH / IH	St/B	**External Bus Interface Address/Data Line 4**
	U0C0_DX2B	I	St/B	**USIC0 Channel 0 Shift Control Input**
	U0C1_DX2B	I	St/B	**USIC0 Channel 1 Shift Control Input**
	ESR1_9	I	St/B	**ESR1 Trigger Input 9**
70	P10.5	O0 / I	St/B	**Bit 5 of Port 10, General Purpose Input/Output**
	U0C1_SCLKOUT	O1	St/B	**USIC0 Channel 1 Shift Clock Output**
	CCU60_COUT62	O2	St/B	**CCU60 Channel 2 Output**
	U2C0_DOUT	O3	St/B	**USIC2 Channel 0 Shift Data Output**
	AD5	OH / IH	St/B	**External Bus Interface Address/Data Line 5**
	U0C1_DX1B	I	St/B	**USIC0 Channel 1 Shift Clock Input**
71	P0.6	O0 / I	St/B	**Bit 6 of Port 0, General Purpose Input/Output**
	U1C1_DOUT	O1	St/B	**USIC1 Channel 1 Shift Data Output**
	TxDC1	O2	St/B	**CAN Node 1 Transmit Data Output**
	CCU61_COUT63	O3	St/B	**CCU61 Channel 3 Output**
	A6	OH	St/B	**External Bus Interface Address Line 6**
	U1C1_DX0A	I	St/B	**USIC1 Channel 1 Shift Data Input**
	CCU61_CTRAPA	I	St/B	**CCU61 Emergency Trap Input**
	U1C1_DX1B	I	St/B	**USIC1 Channel 1 Shift Clock Input**

Table 6 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
72	P10.6	O0 / I	St/B	**Bit 6 of Port 10, General Purpose Input/Output**
	U0C0_DOUT	O1	St/B	**USIC0 Channel 0 Shift Data Output**
	TxDC4	O2	St/B	**CAN Node 4 Transmit Data Output**
	U1C0_SELO0	O3	St/B	**USIC1 Channel 0 Select/Control 0 Output**
	AD6	OH / IH	St/B	**External Bus Interface Address/Data Line 6**
	U0C0_DX0C	I	St/B	**USIC0 Channel 0 Shift Data Input**
	U1C0_DX2D	I	St/B	**USIC1 Channel 0 Shift Control Input**
	CCU60_CTRAPA	I	St/B	**CCU60 Emergency Trap Input**
73	P10.7	O0 / I	St/B	**Bit 7 of Port 10, General Purpose Input/Output**
	U0C1_DOUT	O1	St/B	**USIC0 Channel 1 Shift Data Output**
	CCU60_COUT63	O2	St/B	**CCU60 Channel 3 Output**
	AD7	OH / IH	St/B	**External Bus Interface Address/Data Line 7**
	U0C1_DX0B	I	St/B	**USIC0 Channel 1 Shift Data Input**
	CCU60_CCPOS0A	I	St/B	**CCU60 Position Input 0**
	RxDC4C	I	St/B	**CAN Node 4 Receive Data Input**
	T4INB	I	St/B	**GPT12E Timer T4 Count/Gate Input**
74	P0.7	O0 / I	St/B	**Bit 7 of Port 0, General Purpose Input/Output**
	U1C1_DOUT	O1	St/B	**USIC1 Channel 1 Shift Data Output**
	U1C0_SELO3	O2	St/B	**USIC1 Channel 0 Select/Control 3 Output**
	TxDC3	O3	St/B	**CAN Node 3 Transmit Data Output**
	A7	OH	St/B	**External Bus Interface Address Line 7**
	U1C1_DX0B	I	St/B	**USIC1 Channel 1 Shift Data Input**
	CCU61_CTRAPB	I	St/B	**CCU61 Emergency Trap Input**

3.2 External Bus Controller

All external memory access operations are performed by a special on-chip External Bus Controller (EBC). The EBC also controls access to resources connected to the on-chip LXBus (MultiCAN and the USIC modules). The LXBus is an internal representation of the external bus that allows access to integrated peripherals and modules in the same way as to external components.

The EBC can be programmed either to Single Chip Mode, when no external memory is required, or to an external bus mode with the following selections[1)]:

- Address Bus Width with a range of 0 … 24-bit
- Data Bus Width 8-bit or 16-bit
- Bus Operation Multiplexed or Demultiplexed

The bus interface uses Port 10 and Port 2 for addresses and data. In the demultiplexed bus modes, the lower addresses are output separately on Port 0 and Port 1. The number of active segment address lines is selectable, restricting the external address space to 8 Mbytes … 64 Kbytes. This is required when interface lines shall be assigned to Port 2.

External $\overline{\text{CS}}$ signals (address windows plus default) can be generated and output on Port 4 in order to save external glue logic. External modules can be directly connected to the common address/data bus and their individual select lines.

Important timing characteristics of the external bus interface are programmable (with registers TCONCSx/FCONCSx) to allow the user to adapt it to a wide range of different types of memories and external peripherals.
Access to very slow memories or modules with varying access times is supported by a special 'Ready' function. The active level of the control input signal is selectable.

In addition, up to four independent address windows may be defined (using registers ADDRSELx) to control access to resources with different bus characteristics. These address windows are arranged hierarchically where window 4 overrides window 3, and window 2 overrides window 1. All accesses to locations not covered by these four address windows are controlled by TCONCS0/FCONCS0. The currently active window can generate a chip select signal.

The external bus timing is based on the rising edge of the reference clock output CLKOUT. The external bus protocol is compatible with that of the standard C166 Family.

1) Bus modes are switched dynamically if several address windows with different mode settings are used.

3.6 Interrupt System

The architecture of the XC226xN supports several mechanisms for fast and flexible response to service requests; these can be generated from various sources internal or external to the microcontroller. Any of these interrupt requests can be programmed to be serviced by the Interrupt Controller or by the Peripheral Event Controller (PEC).

Using a standard interrupt service the current program execution is suspended and a branch to the interrupt vector table is performed. With the PEC just one cycle is 'stolen' from the current CPU activity to perform the PEC service. A PEC service implies a single byte or word data transfer between any two memory locations with an additional increment of either the PEC source pointer, the destination pointer, or both. An individual PEC transfer counter is implicitly decremented for each PEC service except when performing in the continuous transfer mode. When this counter reaches zero, a standard interrupt is performed to the corresponding source-related vector location. PEC services are particularly well suited to supporting the transmission or reception of blocks of data. The XC226xN has eight PEC channels, each with fast interrupt-driven data transfer capabilities.

With a minimum interrupt response time of 7/11[1)] CPU clocks, the XC226xN can react quickly to the occurrence of non-deterministic events.

Interrupt Nodes and Source Selection

The interrupt system provides 96 physical nodes with separate control register containing an interrupt request flag, an interrupt enable flag and an interrupt priority bit field. Most interrupt sources are assigned to a dedicated node. A particular subset of interrupt sources shares a set of nodes. The source selection can be programmed using the interrupt source selection (ISSR) registers.

External Request Unit (ERU)

A dedicated External Request Unit (ERU) is provided to route and preprocess selected on-chip peripheral and external interrupt requests. The ERU features 4 programmable input channels with event trigger logic (ETL) a routing matrix and 4 output gating units (OGU). The ETL features rising edge, falling edge, or both edges event detection. The OGU combines the detected interrupt events and provides filtering capabilities depending on a programmable pattern match or miss.

Trap Processing

The XC226xN provides efficient mechanisms to identify and process exceptions or error conditions that arise during run-time, the so-called 'Hardware Traps'. A hardware trap causes an immediate system reaction similar to a standard interrupt service (branching

1) Depending if the jump cache is used or not.

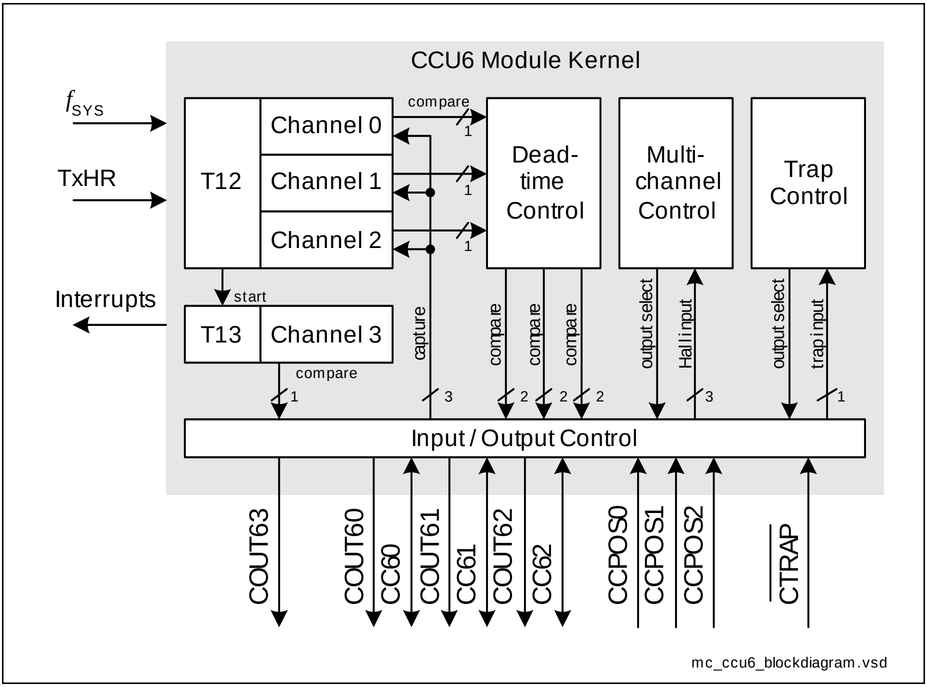

Figure 7 CCU6 Block Diagram

Timer T12 can work in capture and/or compare mode for its three channels. The modes can also be combined. Timer T13 can work in compare mode only. The multi-channel control unit generates output patterns that can be modulated by timer T12 and/or timer T13. The modulation sources can be selected and combined for signal modulation.

3.10 General Purpose Timer (GPT12E) Unit

The GPT12E unit is a very flexible multifunctional timer/counter structure which can be used for many different timing tasks such as event timing and counting, pulse width and duty cycle measurements, pulse generation, or pulse multiplication.

The GPT12E unit incorporates five 16-bit timers organized in two separate modules, GPT1 and GPT2. Each timer in each module may either operate independently in a number of different modes or be concatenated with another timer of the same module.

Each of the three timers T2, T3, T4 of **module GPT1** can be configured individually for one of four basic modes of operation: Timer, Gated Timer, Counter, and Incremental Interface Mode. In Timer Mode, the input clock for a timer is derived from the system clock and divided by a programmable prescaler. Counter Mode allows timer clocking in reference to external events.

Pulse width or duty cycle measurement is supported in Gated Timer Mode, where the operation of a timer is controlled by the 'gate' level on an external input pin. For these purposes each timer has one associated port pin (TxIN) which serves as a gate or clock input. The maximum resolution of the timers in module GPT1 is 4 system clock cycles.

The counting direction (up/down) for each timer can be programmed by software or altered dynamically by an external signal on a port pin (TxEUD), e.g. to facilitate position tracking.

In Incremental Interface Mode the GPT1 timers can be directly connected to the incremental position sensor signals A and B through their respective inputs TxIN and TxEUD. Direction and counting signals are internally derived from these two input signals, so that the contents of the respective timer Tx corresponds to the sensor position. The third position sensor signal TOP0 can be connected to an interrupt input.

Timer T3 has an output toggle latch (T3OTL) which changes its state on each timer overflow/underflow. The state of this latch may be output on pin T3OUT e.g. for time out monitoring of external hardware components. It may also be used internally to clock timers T2 and T4 for measuring long time periods with high resolution.

In addition to the basic operating modes, T2 and T4 may be configured as reload or capture register for timer T3. A timer used as capture or reload register is stopped. The contents of timer T3 is captured into T2 or T4 in response to a signal at the associated input pin (TxIN). Timer T3 is reloaded with the contents of T2 or T4, triggered either by an external signal or a selectable state transition of its toggle latch T3OTL. When both T2 and T4 are configured to alternately reload T3 on opposite state transitions of T3OTL with the low and high times of a PWM signal, this signal can be continuously generated without software intervention.

7) An overload current (I_{OV}) through a pin injects a certain error current (I_{INJ}) into the adjacent pins. This error current adds to the respective pins leakage current (I_{OZ}). The amount of error current depends on the overload current and is defined by the overload coupling factor K_{OV}. The polarity of the injected error current is inverse compared to the polarity of the overload current that produces it.The total current through a pin is $|I_{TOT}| = |I_{OZ}| + (|I_{OV}|\ K_{OV})$. The additional error current may distort the input voltage on analog inputs.

8) Value is controlled by on-chip regulator

4.2 Voltage Range definitions

The XC226xN timing depends on the supply voltage. If such a dependency exists the timing values are given for 2 voltage areas commonly used. The voltage areas are defined in the following tables.

Table 14 Upper Voltage Range Definition

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Digital supply voltage for IO pads and voltage regulators	V_{DDP} SR	4.5	5	5.5	V	

Table 15 Lower Voltage Range Definition

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Digital supply voltage for IO pads and voltage regulators	V_{DDP} SR	3.0	3.3	4.5	V	

4.2.1 Parameter Interpretation

The parameters listed in the following include both the characteristics of the XC226xN and its demands on the system. To aid in correctly interpreting the parameters when evaluating them for a design, they are marked accordingly in the column “Symbol”:

CC (**C**ontroller **C**haracteristics):
The logic of the XC226xN provides signals with the specified characteristics.

SR (**S**ystem **R**equirement):
The external system must provide signals with the specified characteristics to the XC226xN.

Pullup/Pulldown Device Behavior

Most pins of the XC226xN feature pullup or pulldown devices. For some special pins these are fixed; for the port pins they can be selected by the application.

The specified current values indicate how to load the respective pin depending on the intended signal level. **Figure 13** shows the current paths.

The shaded resistors shown in the figure may be required to compensate system pull currents that do not match the given limit values.

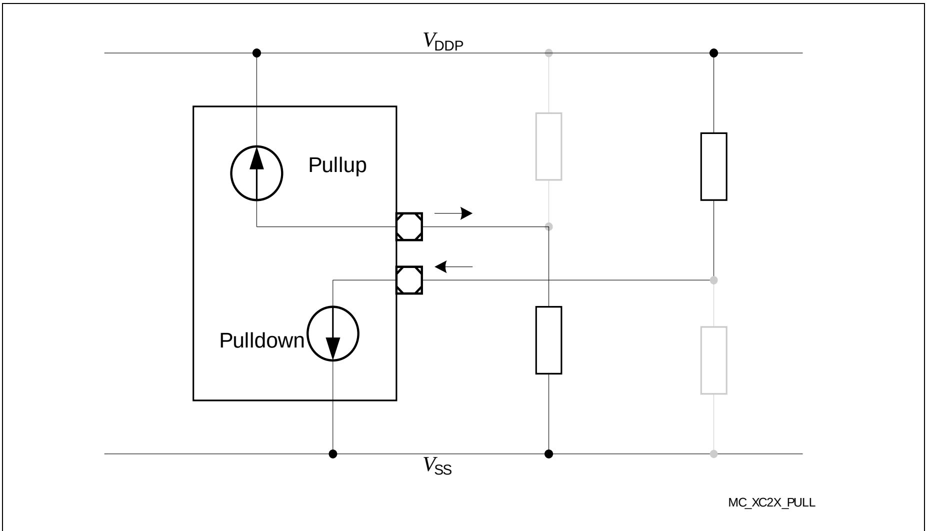

Figure 13 Pullup/Pulldown Current Definition

Table 18 Switching Power Consumption

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Power supply current (active) with all peripherals active and EVVRs on	I_{SACT} CC	–	6 + 0.6 x f_{SYS}[1)]	8 + 1.0 x f_{SYS}[1)]	mA	power_mode= active ; voltage_range= both [2)3)4)]
Power supply current in standby mode	I_{SSB} CC	–	45	125	µA	power_mode= standby ; voltage_range= lower [5)]
		–	70	220	µA	power_mode= standby ; voltage_range= upper [5)]
Power supply current in stopover mode, EVVRs on	I_{SSO} CC	–	0.7	2.0	mA	power_mode= stopover ; voltage_range= both [4)]

1) f_{SYS} in MHz

2) The pad supply voltage pins (V_{DDPB}) provide the input current for the on-chip EVVRs and the current consumed by the pin output drivers. A small current is consumed because the drivers input stages are switched. In Fast Startup Mode (with the Flash modules deactivated), the typical current is reduced to 3 + 0.6 x f_{SYS}.

3) Please consider the additional conditions described in section "Active Mode Power Supply Current".

4) The pad supply voltage has only a minor influence on this parameter.

5) These values are valid if the voltage validation circuits for V_{DDPB} (SWD) and V_{DDIM} (PVC_M) are off. Leaving SWD and PVC_M active adds another 90 µA.

Active Mode Power Supply Current

The actual power supply current in active mode not only depends on the system frequency but also on the configuration of the XC226xN's subsystem.

Besides the power consumed by the device logic the power supply pins also provide the current that flows through the pin output drivers.
A small current is consumed because the drivers' input stages are switched.

The IO power domains can be supplied separately. Power domain A (V_{DDPA}) supplies the A/D converters and Port 6. Power domain B (V_{DDPB}) supplies the on-chip EVVRs and all other ports.

4.4 Analog/Digital Converter Parameters

These parameters describe the conditions for optimum ADC performance.

Note: Operating Conditions apply.

Table 20 ADC Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Switched capacitance at an analog input	C_{AINSW} CC	–	–	4	pF	not subject to production test 1)
Total capacitance at an analog input	C_{AINT} CC	–	–	10	pF	not subject to production test 1)
Switched capacitance at the reference input	C_{AREFSW} CC	–	–	7	pF	not subject to production test 1)
Total capacitance at the reference input	C_{AREFT} CC	–	–	15	pF	not subject to production test 1)
Differential Non-Linearity Error	$\|EA_{DNL}\|$ CC	–	0.8	1	LSB	
Gain Error	$\|EA_{GAIN}\|$ CC	–	0.4	0.8	LSB	
Integral Non-Linearity	$\|EA_{INL}\|$ CC	–	0.8	1.2	LSB	
Offset Error	$\|EA_{OFF}\|$ CC	–	0.5	0.8	LSB	
Analog clock frequency	f_{ADCI} SR	0.5	–	16.5	MHz	voltage_range= lower
		0.5	–	20	MHz	voltage_range= upper
Input resistance of the selected analog channel	R_{AIN} CC	–	–	2	kOhm	not subject to production test 1)
Input resistance of the reference input	R_{AREF} CC	–	–	2	kOhm	not subject to production test 1)

Table 20 ADC Parameters (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Broken wire detection delay against VAGND[2)]	t_{BWG} CC	–	–	50[3)]		
Broken wire detection delay against VAREF[2)]	t_{BWR} CC	–	–	50[4)]		
Conversion time for 8-bit result[2)]	t_{c8} CC	$(11+STC) \times t_{ADCI} + 2 \times t_{SYS}$	–	–		
Conversion time for 10-bit result[2)]	t_{c10} CC	$(13+STC) \times t_{ADCI} + 2 \times t_{SYS}$	–	–		
Total Unadjusted Error	|TUE| CC	–	1	2	LSB	5)
Wakeup time from analog powerdown, fast mode	t_{WAF} CC	–	–	4	µs	
Wakeup time from analog powerdown, slow mode	t_{WAS} CC	–	–	15	µs	
Analog reference ground	V_{AGND} SR	V_{SS} - 0.05	–	1.5	V	
Analog input voltage range	V_{AIN} SR	V_{AGND}	–	V_{AREF}	V	6)
Analog reference voltage	V_{AREF} SR	V_{AGND} + 1.0	–	V_{DDPA} + 0.05	V	

1) These parameter values cover the complete operating range. Under relaxed operating conditions (temperature, supply voltage) typical values can be used for calculation. At room temperature and nominal supply voltage the following typical values can be used: $C_{AINTtyp}$ = 12 pF, $C_{AINStyp}$ = 5 pF, R_{AINtyp} = 1.0 kOhm, $C_{AREFTtyp}$ = 15 pF, $C_{AREFStyp}$ = 10 pF, $R_{AREFtyp}$ = 1.0 kOhm.

2) This parameter includes the sample time (also the additional sample time specified by STC), the time to determine the digital result and the time to load the result register with the conversion result. Values for the basic clock t_{ADCI} depend on programming.

3) The broken wire detection delay against V_{AGND} is measured in numbers of consecutive precharge cycles at a conversion rate of not more than 500 µs. Result below 10% (66_H)

Table 26 System PLL Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
VCO output frequency	f_{VCO} CC	50	–	110	MHz	*VCOSEL*= 00b; *VCOmode*= controlled
		10	–	40	MHz	*VCOSEL*= 00b; *VCOmode*= free running
		100	–	160	MHz	*VCOSEL*= 01b; *VCOmode*= controlled
		20	–	80	MHz	*VCOSEL*= 01b; *VCOmode*= free running

4.7.2.2 Wakeup Clock

When wakeup operation is selected (SYSCON0.CLKSEL = 00_B), the system clock is derived from the low-frequency wakeup clock source:

$f_{SYS} = f_{WU}$.

In this mode, a basic functionality can be maintained without requiring an external clock source and while minimizing the power consumption.

4.7.2.3 Selecting and Changing the Operating Frequency

When selecting a clock source and the clock generation method, the required parameters must be carefully written to the respective bit fields, to avoid unintended intermediate states.

Many applications change the frequency of the system clock (f_{SYS}) during operation in order to optimize system performance and power consumption. Changing the operating frequency also changes the switching currents, which influences the power supply.

To ensure proper operation of the on-chip EVRs while they generate the core voltage, the operating frequency shall only be changed in certain steps. This prevents overshoots and undershoots of the supply voltage.

To avoid the indicated problems, recommended sequences are provided which ensure the intended operation of the clock system interacting with the power system.
Please refer to the Programmer's Guide.

1) The amplitude voltage V_{AX1} refers to the offset voltage V_{OFF}. This offset voltage must be stable during the operation and the resulting voltage peaks must remain within the limits defined by V_{IX1}.
2) Overload conditions must not occur on pin XTAL1.

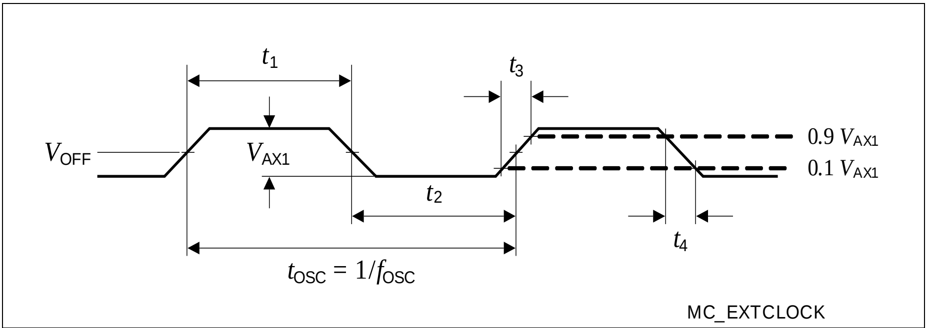

Figure 21 External Clock Drive XTAL1

Note: For crystal or ceramic resonator operation, it is strongly recommended to measure the oscillation allowance (negative resistance) in the final target system (layout) to determine the optimum parameters for oscillator operation.
The manufacturers of crystals and ceramic resonators offer an oscillator evaluation service. This evaluation checks the crystal/resonator specification limits to ensure a reliable oscillator operation.

4.7.5 External Bus Timing

The following parameters specify the behavior of the XC226xN bus interface.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply.

Table 30 Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
CLKOUT Cycle Time[1)]	t_5 CC	–	$1 / f_{SYS}$	–	ns	
CLKOUT high time	t_6 CC	3	–	–		
CLKOUT low time	t_7 CC	3	–	–		
CLKOUT rise time	t_8 CC	–	–	3	ns	
CLKOUT fall time	t_9 CC	–	–	3		

1) The CLKOUT cycle time is influenced by PLL jitter. For longer periods the relative deviation decreases (see PLL deviation formula).

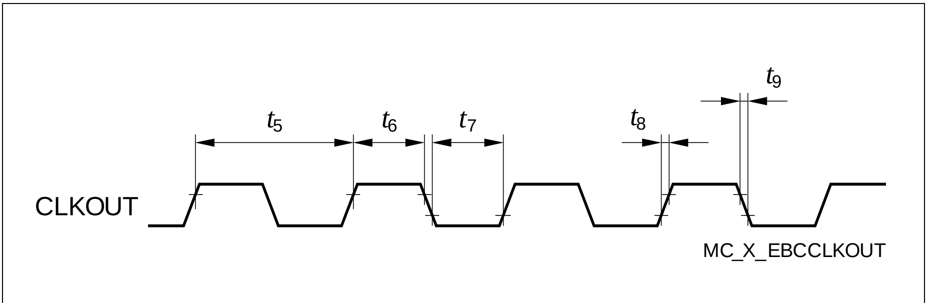

Figure 22 CLKOUT Signal Timing

Note: The term CLKOUT refers to the reference clock output signal which is generated by selecting f_{SYS} as the source signal for the clock output signal EXTCLK on pin P2.8 and by enabling the high-speed clock driver on this pin.

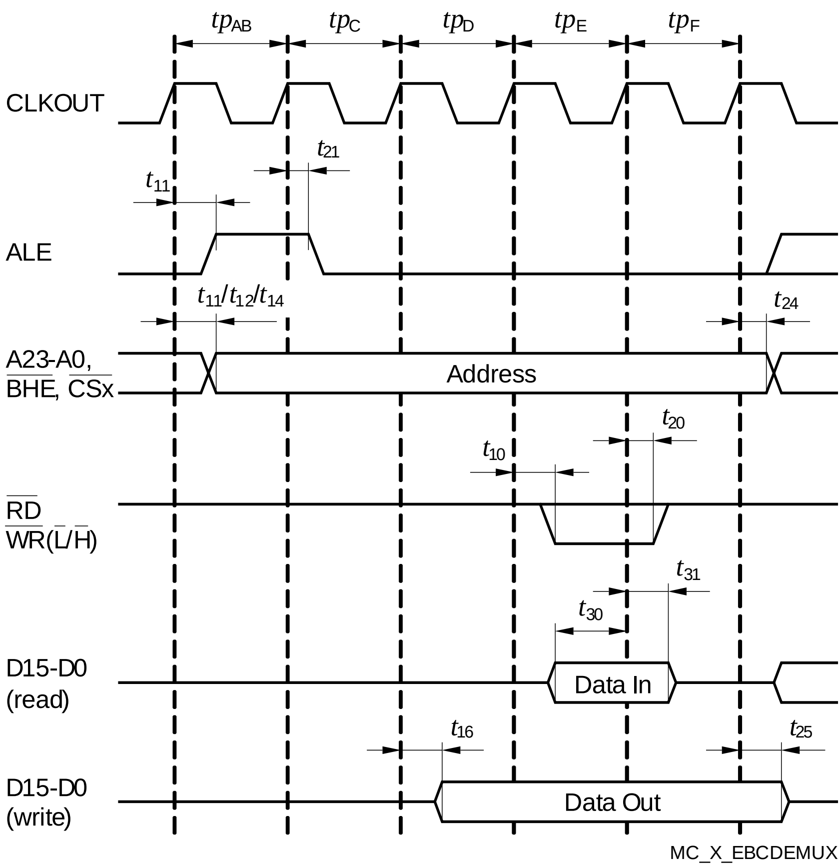

Figure 24 Demultiplexed Bus Cycle

4.7.5.1 Bus Cycle Control with the READY Input

The duration of an external bus cycle can be controlled by the external circuit using the READY input signal. The polarity of this input signal can be selected.

Synchronous READY permits the shortest possible bus cycle but requires the input signal to be synchronous to the reference signal CLKOUT.

An asynchronous READY signal puts no timing constraints on the input signal but incurs a minimum of one waitstate due to the additional synchronization stage. The minimum

Table 36 USIC SSC Slave Mode Timing for Upper Voltage Range (cont'd)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Data input DX0 hold time from clock input DX1 receive edge[1]	t_{13} SR	5	–	–	ns	
Data output DOUT valid time	t_{14} CC	7	–	33	ns	

1) These input timings are valid for asynchronous input signal handling of slave select input, shift clock input, and receive data input (bits DXnCR.DSEN = 0).

Table 37 is valid under the following conditions: C_L= 20 pF; SSC= slave ; voltage_range= lower

Table 37 USIC SSC Slave Mode Timing for Lower Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Select input DX2 setup to first clock input DX1 transmit edge[1]	t_{10} SR	7	–	–	ns	
Select input DX2 hold after last clock input DX1 receive edge[1]	t_{11} SR	7	–	–	ns	
Receive data input setup time to shift clock receive edge[1]	t_{12} SR	7	–	–	ns	
Data input DX0 hold time from clock input DX1 receive edge[1]	t_{13} SR	5	–	–	ns	
Data output DOUT valid time	t_{14} CC	8	–	41	ns	

1) These input timings are valid for asynchronous input signal handling of slave select input, shift clock input, and receive data input (bits DXnCR.DSEN = 0).

4.7.7 Debug Interface Timing

The debugger can communicate with the XC226xN either via the 2-pin DAP interface or via the standard JTAG interface.

Debug via DAP

The following parameters are applicable for communication through the DAP debug interface.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Note: Operating Conditions apply.

Table 38 is valid under the following conditions: C_L= 20 pF; voltage_range= upper

Table 38 DAP Interface Timing for Upper Voltage Range

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
DAP0 clock period[1)]	t_{11} SR	25	–	–	ns	
DAP0 high time	t_{12} SR	8	–	–	ns	
DAP0 low time[1)]	t_{13} SR	8	–	–	ns	
DAP0 clock rise time	t_{14} SR	–	–	4	ns	
DAP0 clock fall time	t_{15} SR	–	–	4	ns	
DAP1 setup to DAP0 rising edge	t_{16} SR	6	–	–	ns	
DAP1 hold after DAP0 rising edge	t_{17} SR	6	–	–	ns	
DAP1 valid per DAP0 clock period[2)]	t_{19} CC	17	20	–	ns	

1) See the DAP chapter for clock rate restrictions in the Active::IDLE protocol state.

2) The Host has to find a suitable sampling point by analyzing the sync telegram response.

Table 39 is valid under the following conditions: C_L= 20 pF; voltage_range= lower

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